

Empirical analysis of software-induced failure events in the nuclear industry

Fan CF, Yih S, Tseng WH, Chen WC.

Safety science

2013; 57:118-128

ARTICLE IDENTIFIERS

DOI: 10.1016/j.ssci.2013.02.001

PMID: unavailable

PMCID: not available

JOURNAL IDENTIFIERS

LCCN: 91640944

pISSN: 0925-7535

eISSN: 1879-1042

OCLC ID: 23966897

CONS ID: sn 91-38208

US National Library of Medicine ID: 9114980

This article was identified from a query of the SafetyLit database.